## IN THE SPECIFICATION:

Please replace paragraph [0029] with the following amended paragraph:

[0029] Figures 3A-C illustrate one embodiment of the alternating chemisorption of monolayers of a tantalum containing compound and a nitrogen containing compound on an exemplary portion of substrate 300 in a stage of integrated circuit fabrication, and more particularly at a stage of barrier layer formation. In Figure 3A, a monolayer of a tantalum containing compound is chemisorbed on the substrate 300 by introducing a pulse of the tantalum containing compound 305 into a process chamber, such as a process chamber shown in Figure 1. It is believed that the chemisorption processes used to absorb the monolayer of the tantalum containing compound 305 are self-limiting in that only one monolayer may be chemisorbed onto the surface of the substrate 300 during a given pulse because the surface of the substrate has a finite number of sites for chemisorbing the tantalum containing compound. Once the finite number of sites are is occupied by the tantalum containing compound 305, further ehemisorportion chemisorption of any tantalum containing compound will be blocked.

Please replace paragraph [0031] with the following amended paragraph:

[0031] The tantalum containing compounds may be other organo-metallic precursors or derivatives thereof such as, but not limited to pentaethylmethylamino-tantalum (PEMAT;  $\underline{Ta(N(Et)Me)_5}$   $\underline{Ta[N(C_2H_5CH_3)_2]_6}$ ), pentadiethylamino-tantalum (PDEAT;  $Ta(NEt_2)_5$ ,), and any and all of derivatives of PEMAT, PDEAT, or PDMAT. Other tantalum containing compounds include without limitation TBTDET ( $Ta(NEt_2)_3NC_4H_9$  or  $C_{16}H_{39}N_4Ta$ ) and tantalum halides, for example  $TaX_5$  where X is fluorine (F), bromine (Br) or chlorine (Cl), and derivatives thereof.

Please replace paragraph [0034] with the following amended paragraph:

Referring to Figure 3B, after the process chamber has been purged, a pulse of a nitrogen containing compound 325 is introduced into the process chamber. The nitrogen containing compound 325 may be provided alone or may be provided with the aid of a carrier gas. The nitrogen containing compound 325 may comprise nitrogen atoms 330 with one or more reactive species 335. The nitrogen containing compound preferably comprises ammonia gas (NH<sub>3</sub>). Other nitrogen containing compounds may be used which include, but are not limited to, N<sub>x</sub>H<sub>y</sub> with x and y being integers (*e.g.*, hydrazine (N<sub>2</sub>H<sub>4</sub>)), dimethyl hydrazine ((CH<sub>3</sub>)<sub>2</sub>N2H<sub>2</sub>) (((CH<sub>3</sub>)<sub>2</sub>N<sub>2</sub>H<sub>2</sub>), t-butylhydrazine (C<sub>4</sub>H<sub>9</sub>N<sub>2</sub>H<sub>3</sub>) phenylhydrazine (C<sub>6</sub>H<sub>5</sub>N<sub>2</sub>H<sub>3</sub>), other hydrazine derivatives, a nitrogen plasma source (*e.g.*, N<sub>2</sub>, N<sub>2</sub>/H<sub>2</sub>, NH<sub>3</sub>, or a N<sub>2</sub>H<sub>4</sub> plasma), 2,2'-azoisobutane ((CH<sub>3</sub>)<sub>6</sub>C<sub>2</sub>N<sub>2</sub>), ethylazide (C<sub>2</sub>H<sub>5</sub>N<sub>3</sub>), and other suitable gases. A carrier gas may be used to deliver the nitrogen containing compound if necessary.